	Type	Hits	Search Text	DBs
1	BRS	3380	361/56	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
2	BRS	116	MOSFET same gate adj (leak leakage)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
3	BRS	29	MOSFET same gate adj (leak leakage) same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
4	BRS	1	MOSFET same gate adj (leak leakage) same substrate same gate adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
5	BRS	0	MOSFET same gate adj (leak leakage) same substrate same drain adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
6	BRS	1	MOSFET same gate adj (leak leakage) same drain adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	3	MOSFET and gate adj (leak leakage) same drain adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
8	BRS	29	MOSFET same gate adj (leak leakage) same gate same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
9	BRS	0	MOSFET same gate adj (leak leakage) same gate adj2 (bias biasing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10	BRS	11	6,064,158	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
11	BRS	13	5,864,162	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
12	BRS	15	5,847,516	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
13	BRS	16	MOSFET same source adj current same gate adj (bias biasing)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
14	BRS	123	MOSFET same source adj current same source adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
15	BRS	2	MOSFET same source adj leak same source adj voltage	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
16	BRS	71	esd same MOSFET same trigger	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
17	BRS	24	esd same MOSFET same trigger same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Time Stamp	Comments	Error Definition	Errors
1	2003/04/10 09:29			0
2	2003/04/10 09:40			0
3	2003/04/10 09:59			0
4	2003/04/10 09:35			0
5	2003/04/10 09:35			0
6	2003/04/10 09:36			0
7	2003/04/10 09:37			0
8	2003/04/10 09:46			0
9	2003/04/10 10:08			0
10	2003/04/10 10:01			0
11	2003/04/10 10:03			0
12	2003/04/10 10:03			0
13	2003/04/10 10:18			0
14	2003/04/10 10:28			0
15	2003/04/10 11:15			0
16	2003/04/10 11:45			0
17	2003/04/10 11:27			0

	Type	Hits	Search Text	DBs
18	BRS	26	esd same MOSFET same (trigger triggering) same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
19	BRS	17	("4595941" | "4835416" | "4890187" | "4918563" | "4922371" | "4978867" | "4980792" | "4982113" | "5041889" | "5121007" | "5124578" | "5134314" | "5189588" | "5239440" | "5287241" | "5343352" | "5345357").PN.	USPAT
20	BRS	17	("4595941" | "4835416" | "4890187" | "4918563" | "4922371" | "4978867" | "4980792" | "4982113" | "5041889" | "5121007" | "5124578" | "5134314" | "5189588" | "5239440" | "5287241" | "5343352" | "5345357").PN.	USPAT
21	BRS	8	5,852,541	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
22	BRS	6	5,959,488	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
23	BRS	14	4,609,488	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
24	BRS	24	4,609,931	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
25	BRS	32	esd same MOSFET same (leak leakage)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
26	BRS	12	esd same MOSFET same (leak leakage) same substrate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
27	BRS	3	("5530612" | "5539327" | "5565790").PN.	USPAT
28	BRS	3	5903419.URPN.	USPAT
29	BRS	2730	361/111	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
30	BRS	1179	361/91.5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
31	BRS	37	esd same (plurality multiple) adj (inputs outputs)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Time Stamp	Comments	Error Definition	Errors
18	2003/04/10 11:28			0
19	2003/04/10 11:31			0
20	2003/04/10 11:35			0
21	2003/04/10 13:13			0
22	2003/04/10 13:47			0
23	2003/04/10 13:17			0
24	2003/04/10 13:17			0
25	2003/04/10 13:50			0
26	2003/04/10 16:44			0
27	2003/04/10 13:58			0
28	2003/04/10 14:23			0
29	2003/04/10 16:44			0
30	2003/04/11 09:10			0
31	2003/04/11 15:57			0

	Type	Hits	Search Text	DBs
32	BRS	5	5,751,507	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

	Time Stamp	Comments	Error Definition	Errors
32	2003/04/11 15:57			0